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Substitute for	r Form 1449A/P1			Application Number	Unknown		
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STATEMENT BY APPLICANT				First Named Inventor	Donald J. Svetkoff et al.		
		•		Group Art Unit	Unknown		
(use as many sheets as necessary)				Examiner Name	Unknown		
Sheet	1	of	3	Attorney Docket Number	GSIL 0186 PUS 2		

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Examiner Initials	Cite No.1	Office ³	Number ⁴	Kind Code ⁸ (if known)	Name of Patentee or Applicant of Cited Document	of Cited Document MM-DD-YYYY	Passages or Relevant Figures Appear	_
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STATE	EMENT BY	APF	PLICANT	First Named Inventor	Donald J. Svetkoff et al.		
				Group Art Unit	Unknown .		
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Sheet	2	of	3	Attorney Docket Number	GSIL 0186 PUS 2		

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000000000000000000000000000000000000000			0.00155	Application Number	Unknown				
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Sheet	3	of	3	Attorney Docket Number	GSIL 0186 PUS 3				
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